

FMH22N60S1FD-VB Datasheet

N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY				
V _{DS} (V) at T _J max.	650			
R _{DS(on)} (Ω) at 25 °C	V _{GS} = 10 V	0.19		
Q _g max. (nC)	106			
Q _{gs} (nC)	14			
Q _{gd} (nC)	33			
Configuration	Single			

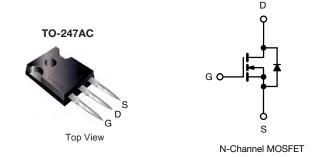
FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Qa)
- Avalanche energy rated (UIS)



APPLICATIONS

- Telecommunications
 - Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Consumer and computing
 - ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
 - Solar (PV inverters)
- Switch mode power supplies (SMPS)



ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	650	V	
Gate-Source Voltage			V_{GS}	± 30	7 v	
Continuous Drain Current (T _J = 150 °C)	V _{GS} at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	I _D	20		
	V _{GS} at 10 V	T _C = 100 °C		13	Α	
Pulsed Drain Current ^a			I _{DM}	53		
Linear Derating Factor				1.7	W/°C	
Single Pulse Avalanche Energy b			E _{AS}	367	mJ	
Maximum Power Dissipation			P_{D}	208	W	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Drain-Source Voltage Slope	T _J = 125 °C		dV/dt	37	V/ns	
Reverse Diode dV/dt ^d		uv/at	31	V/IIS		
Soldering Recommendations (Peak Temperature) c	for 10 s			300	°C	

- a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD}=50~V$, starting $T_J=25~^{\circ}C$, L=28.2~mH, $R_g=25~\Omega$, $I_{AS}=5.1~A$.
- c. 1.6 mm from case.
- d. $I_{SD} \le I_D$, dI/dt = 100 A/ μ s, starting $T_J = 25$ °C.

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.5	G/ VV	

PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		2	-	4	٧
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
			V _{GS} = ± 30 V		-	± 1	μΑ
7 0 1 1/1 5 1 0 1	,	$V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}$		-	-	1	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 520 V, V _{GS} = 0 V, T _J = 125 °C		-	-	500	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 11 A	-	0.19	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 30 V, I _D = 11 A		-	7.0	_	S
Dynamic							•
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 100 V, f = 1 MHz		-	2322	-	pF
Output Capacitance	C _{oss}			-	105	-	
Reverse Transfer Capacitance	C _{rss}			-	4	-	
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	- V _{DS} = 0 V to 520 V, V _{GS} = 0 V		-	84	-	
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	293	-	
Total Gate Charge	Qg			-	71	106	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 11 \text{ A}, V_{DS} = 520 \text{ V}$	-	14	-	nC	
Gate-Drain Charge	Q _{gd}				33		-
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 520 \text{ V, } I_{D} = 11 \text{ A,}$ $V_{GS} = 10 \text{ V, } R_{g} = 9.1 \Omega$		-	22	44	ns
Rise Time	t _r			-	34	68	
Turn-Off Delay Time	t _{d(off)}			-	68	102	
Fall Time	t _f			-	42	84	
Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	21	
Pulsed Diode Forward Current	I _{SM}			-	-	53	- A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V		-	0.9	1.2	V
Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = I_S = 11 \text{ A},$ $dI/dt = 100 \text{ A/µs}, V_R = 25 \text{ V}$		-	160	-	ns
Reverse Recovery Charge	Q _{rr}			-	1.2	-	μC
Reverse Recovery Current	I _{RRM}			_	14	-	A

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .

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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

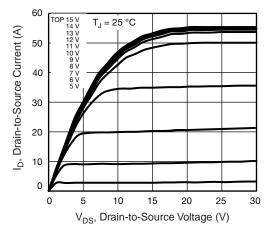


Fig. 1 - Typical Output Characteristics

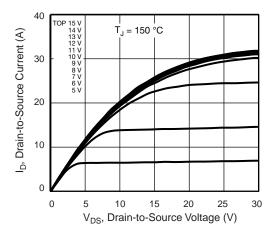


Fig. 2 - Typical Output Characteristics

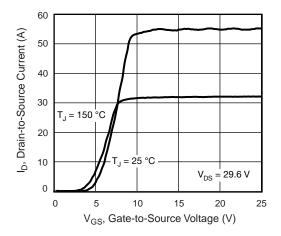


Fig. 3 - Typical Transfer Characteristics

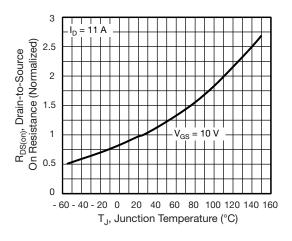


Fig. 4 - Normalized On-Resistance vs. Temperature

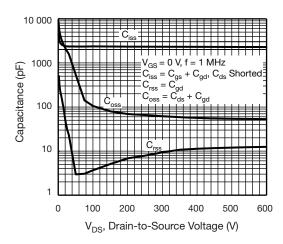


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

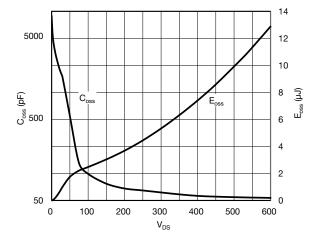


Fig. 6 - $\mathrm{C}_{\mathrm{oss}}$ and $\mathrm{E}_{\mathrm{oss}}$ vs. V_{DS}

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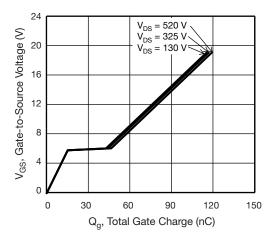


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

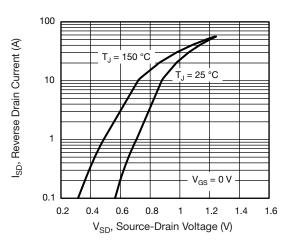


Fig. 8 - Typical Source-Drain Diode Forward Voltage

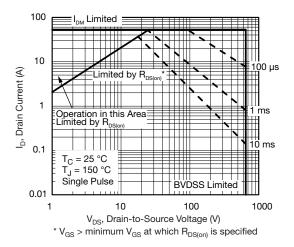


Fig. 9 - Maximum Safe Operating Area

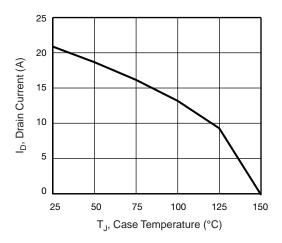


Fig. 10 - Maximum Drain Current vs. Case Temperature

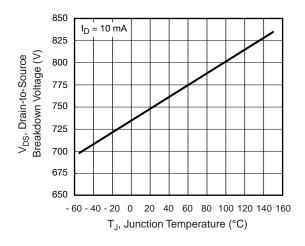


Fig. 11 - Temperature vs. Drain-to-Source Voltage



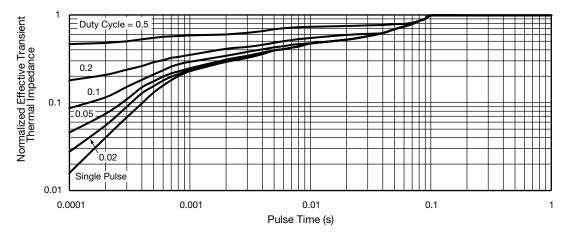


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

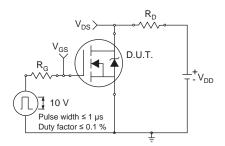


Fig. 13 - Switching Time Test Circuit

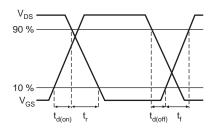


Fig. 14 - Switching Time Waveforms

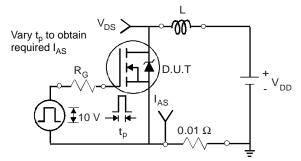


Fig. 15 - Unclamped Inductive Test Circuit

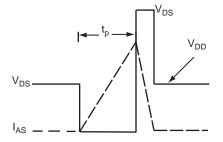


Fig. 16 - Unclamped Inductive Waveforms

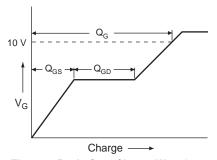


Fig. 17 - Basic Gate Charge Waveform

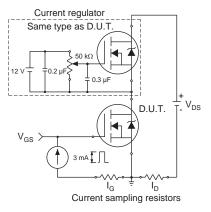
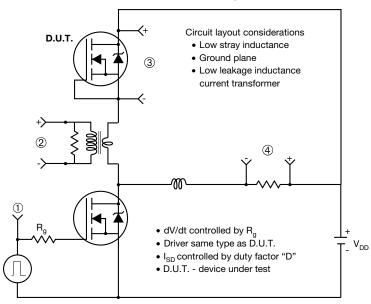


Fig. 18 - Gate Charge Test Circuit

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Peak Diode Recovery dV/dt Test Circuit



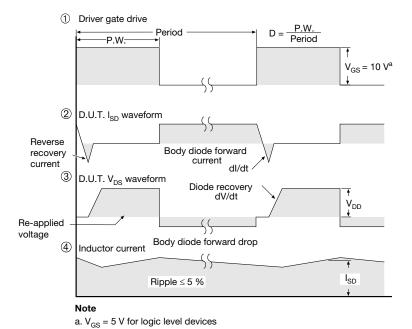


Fig. 19 - For N-Channel



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